

OptiMOS® Power-Transistor

Features

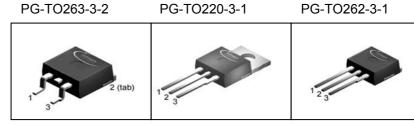
- N-channel Enhancement mode
- Automotive AEC Q101 qualified
- MSL1 up to 260°C peak reflow

• 175°C operating temperature

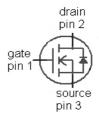
- Green package (lead free)
- Ultra low Rds(on)
- 100% Avalanche tested

Product Summary

V _{DS}	75	V
R _{DS(on),max} (SMD version)	7.1	mΩ
I _D	80	Α



Туре	Package	Ordering Code	Marking
IPB80N08S2-07	PG-TO263-3-2	SP0002-19048	2N0807
IPP80N08S2-07	PG-TO220-3-1	SP0002-19040	2N0807
IPI80N08S2-07	PG-TO262-3-1	SP0002-19043	2N0807



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current ¹⁾	I _D	T _C =25 °C, V _{GS} =10 V	80	Α
		T _C =100 °C, V _{GS} =10 V ²⁾	80	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	320	
Avalanche energy, single pulse ²⁾	E _{AS}	/ _D =80A	810	mJ
Gate source voltage ⁴⁾	V_{GS}		±20	V
Power dissipation	P _{tot}	T _C =25 °C	300	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 +175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

IPB80N08S2-07 IPP80N08S2-07, IPI80N08S2-07

Parameter	Symbol	Conditions		Values	/alues	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}		-	-	0.5	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}		-	-	62	
SMD version, device on PCB R_{th}	R_{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ⁵⁾	-	-	40	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D = 1 mA	75	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	V _{DS} =V _{GS} , I _D =250 μA	2.1	3.0	4.0	
Zero gate voltage drain current	I _{DSS}	V _{DS} =75 V, V _{GS} =0 V, T _j =25 °C	-	0.01	1	μΑ
		$V_{\rm DS}$ =75 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C ²⁾	-	1	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	1	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =80 A,	1	5.8	7.4	mΩ
		$V_{\rm GS}$ =10 V, $I_{\rm D}$ =80 A, SMD version		5.5	7.1	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	4700	-	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =25 V, f=1 MHz	-	1260	-	1
Reverse transfer capacitance	C _{rss}		-	580	-	1
Turn-on delay time	t _{d(on)}		-	26	-	ns
Rise time	t _r	V _{DD} =40 V, V _{GS} =10 V,	-	50	-	
Turn-off delay time	$t_{\text{d(off)}}$	$I_{\rm D}$ =80 A, $R_{\rm G}$ =2.2 Ω	-	61	-	
Fall time	$t_{\rm f}$		-	30	-	
Gate Charge Characteristics ²⁾						
Gate to source charge	Q _{gs}		-	25	37	nC
Gate to drain charge	Q_{gd}	$V_{\rm DD}$ =60 V, $I_{\rm D}$ =80 A, $V_{\rm GS}$ =0 to 10 V	-	69	116	<u> </u>
Gate charge total	Qg		-	144	180	
Gate plateau voltage	V_{plateau}		ı	5.4	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	- T _C =25 °C	-	-	80	А
Diode pulse current ²⁾	I _{S,pulse}	7 _C =25 C	-	-	320	1
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =80 A, T _j =25 °C	-	0.9	1.3	V
Reverse recovery time ²⁾	t _{rr}	V _R =40 V, I _F =I _S , di _F /dt=100 A/μs	-	110	140	ns
Reverse recovery charge ²⁾	Q _{rr}	V_R =40 V, I_F = I_S , di_F / dt =100 A/ μ s	-	470	590	nC

¹⁾ Current is limited by bondwire; with an $R_{\rm thJC}$ = 0.5K/W the chip is able to carry 132A at 25°C. For detailed information see Application Note ANPS071E at www.infineon.com/optimos

²⁾ Defined by design. Not subject to production test.

³⁾ See diagram 13.

⁴⁾ Qualified at -20V and +20V.

 $^{^{5)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

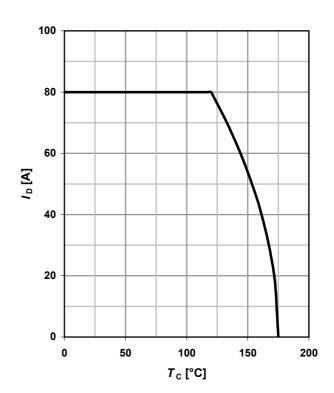


1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

2 Drain current

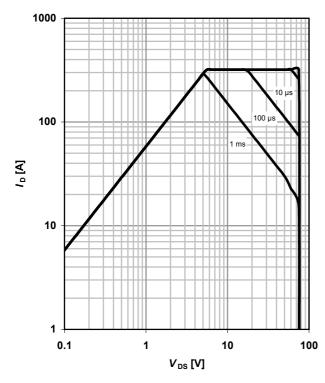
$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$



3 Safe operating area

$$I_D = f(V_{DS}); T_C = 25 \,^{\circ}C; D = 0$$

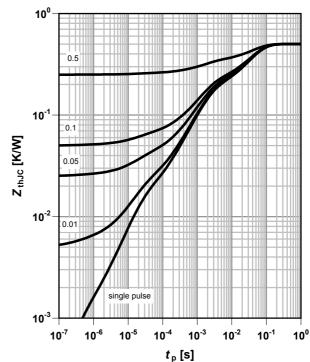
parameter: t_p



4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D = t_p/T$

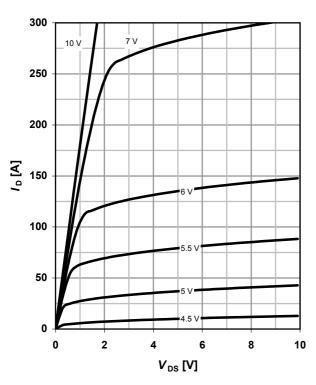




5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,{}^{\circ}{\rm C}$

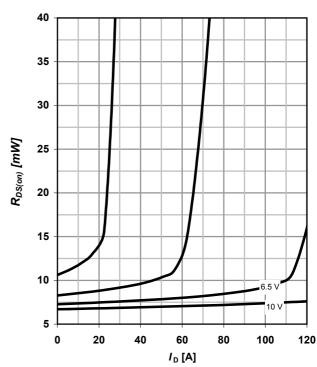
parameter: $V_{\rm GS}$



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ °C}$

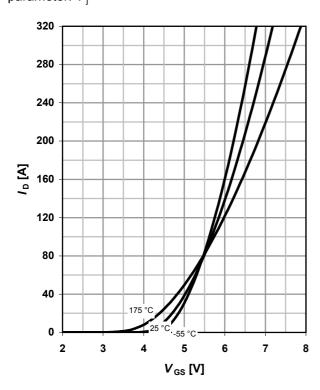
parameter: V_{GS}



7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6V$

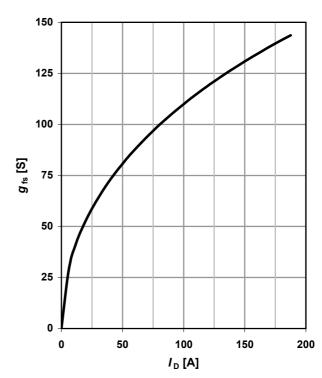
parameter: T_i



8 Typ. Forward transconductance

 $g_{fs} = f(I_D); T_j = 25^{\circ}C$

parameter: g fs

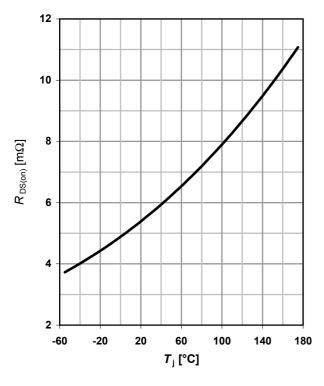




9 Typ. Drain-source on-state resistance

 $R_{DS(ON)} = f(T_j)$

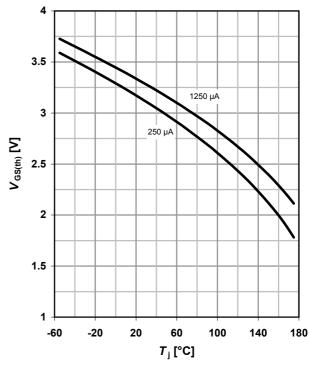
parameter: I_D = 80 A; V_{GS} = 10 V



10 Typ. gate threshold voltage

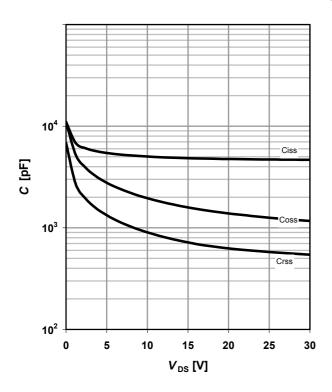
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D



11 Typ. capacitances

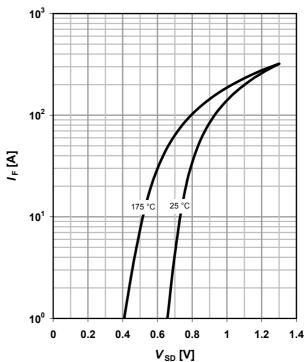
 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$



12 Typical forward diode characteristicis

 $IF = f(V_{SD})$

parameter: T_i

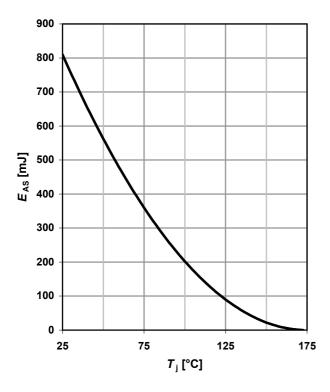




13 Typical avalanche energy

 $E_{AS} = f(T_i)$

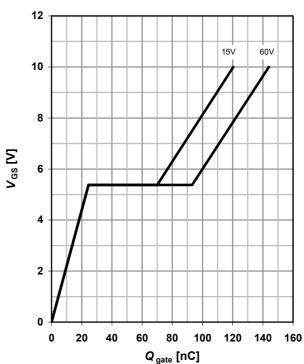
parameter: I_D = 80A



14 Typ. gate charge

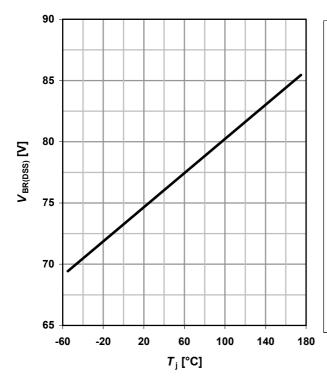
 V_{GS} = f(Q_{gate}); I_D = 80 A pulsed

parameter: V_{DD}

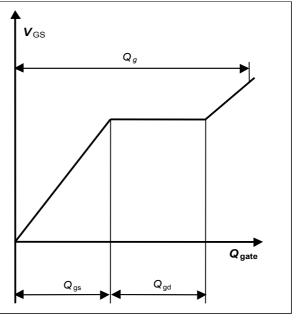


15 Typ. drain-source breakdown voltage

 $V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$



16 Gate charge waveforms





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